



Form PTO-1449 (Modified)

U.S. Department of Commerce
Patent and Trademark OfficeAttorney Docket No.
30203/37899Serial No.
09/996,143**INFORMATION DISCLOSURE
STATEMENT**Applicant
R. FrickFiling Date
11/28/01Group
2877**U.S. PATENT DOCUMENTS**

*Examiner Initials	Document Number	Issue Date	Name	Class	Subclass	Filing Date If Appropriate
La	4,452,533	06/05/84	Miles et al.			
La	4,955,028	09/04/90	Alferness et al.			
La	5,097,476	03/17/92	Thiessen			
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						Yes	No
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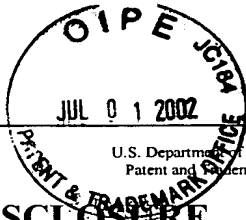
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						Yes	No
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<i>LO</i>	WO 95/13638	05/18/95	PCT				

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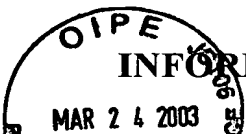
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<i>ca</i>	United States Patent Application Publication - US 2002/0154860; Published: 10-24-02

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